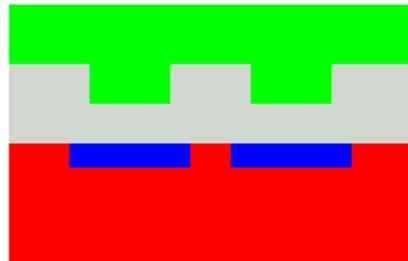


# LECTURE-15

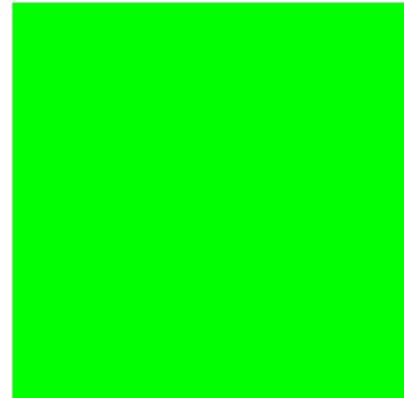
# PR Applied

The second photolithography process is done to remove the oxide, defining a gate region. The same procedure (PR Drop -> Spinning -> Pre-Baking -> Mask Alignment -> UV Exposure -> PR Developing -> Rinsing and Drying -> Post-Baking -> Oxide Etching) as in Lithography #1 is used.

PR applied.



Side View

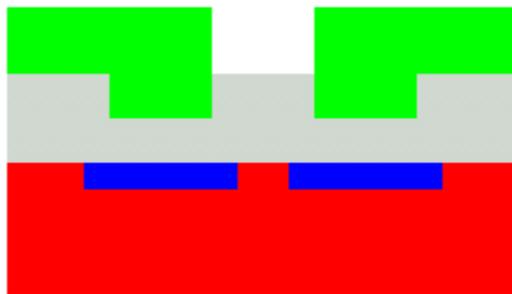


Top View

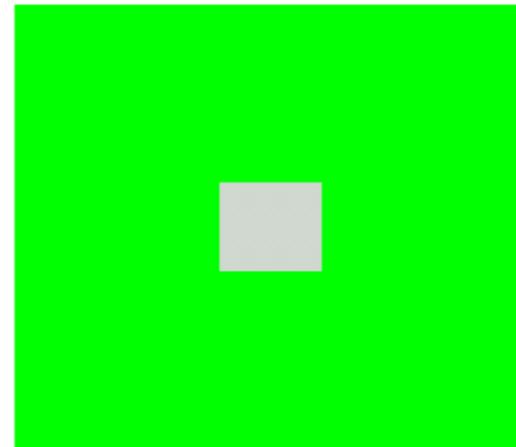
# PR Developed

The second photolithography process is done to remove the oxide, defining a gate region. The same procedure (PR Drop -> Spinning -> Pre-Baking -> Mask Alignment -> UV Exposure -> PR Developing -> Rinsing and Drying -> Post-Baking -> Oxide Etching) as in Lithography #1 is used.

PR developed.



Side View



Top View

■ P-type Silicon

■ N-type Silicon

■ Silicon Dioxide

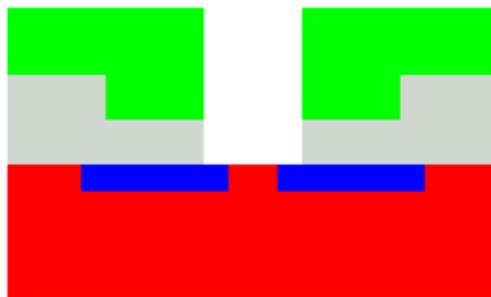
■ Photoresist

■ Aluminum

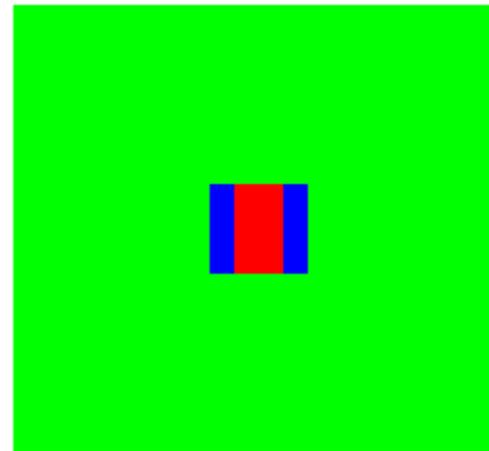
# Oxide Etched

The second photolithography process is done to remove the oxide, defining a gate region. The same procedure (PR Drop -> Spinning -> Pre-Baking -> Mask Alignment -> UV Exposure -> PR Developing -> Rinsing and Drying -> Post-Baking -> Oxide Etching) as in Lithography #1 is used.

Oxide etched.



Side View

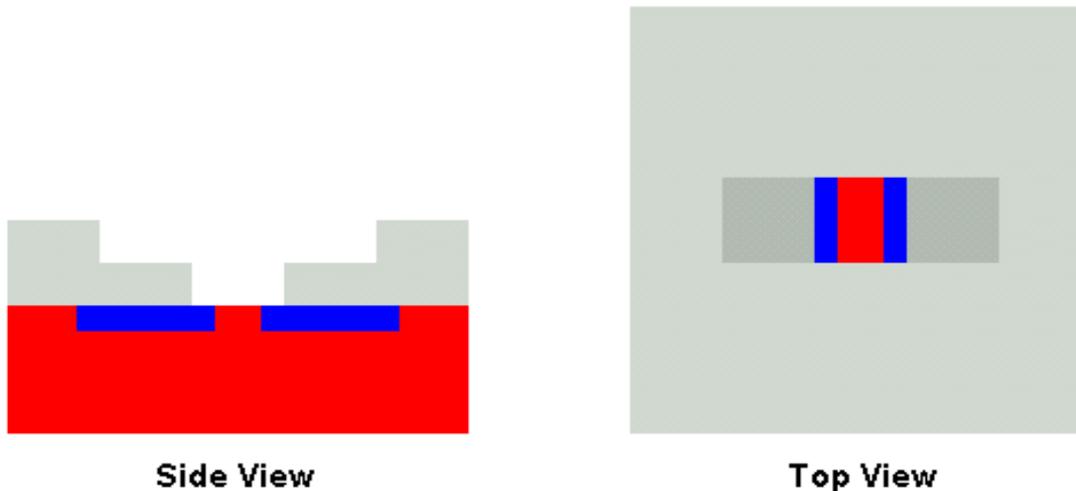


Top View

# PR Stripped

The second photolithography process is done to remove the oxide, defining a gate region. The same procedure (PR Drop -> Spinning -> Pre-Baking -> Mask Alignment -> UV Exposure -> PR Developing -> Rinsing and Drying -> Post-Baking -> Oxide Etching) as in Lithography #1 is used.

PR stripped.



■ P-type Silicon

■ N-type Silicon

■ Silicon Dioxide

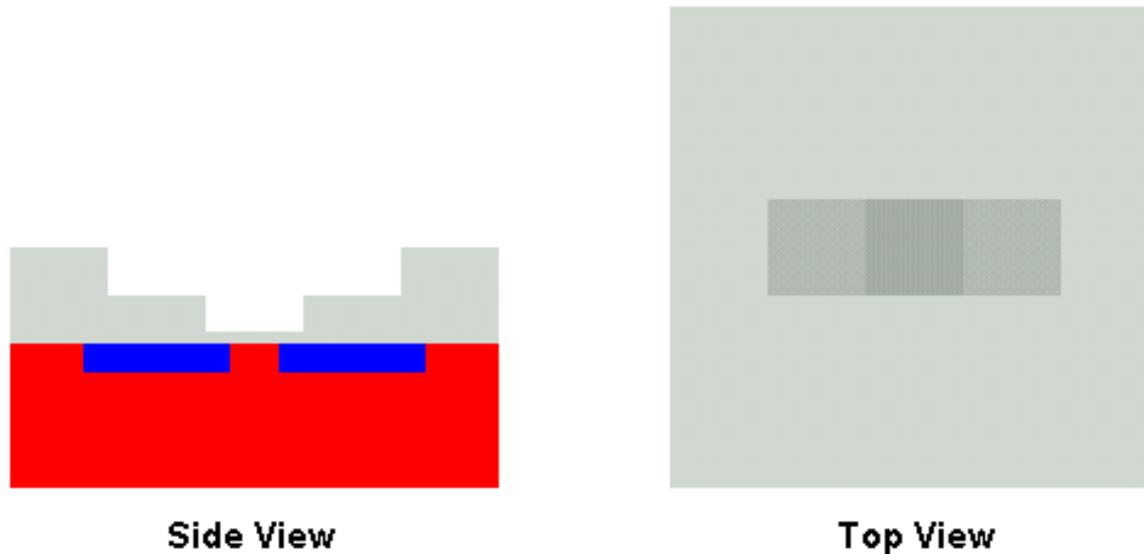
■ Photoresist

■ Aluminum

# Gate Oxide Grown

After the second photolithography, a very thin gate oxide layer (a few hundred angstroms) is grown by thermal oxidation.

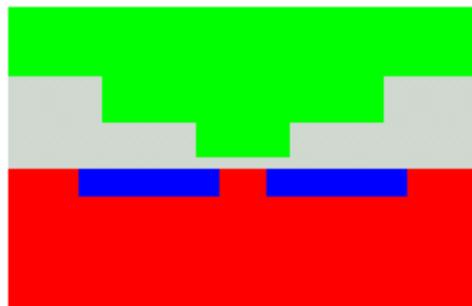
Gate Oxide grown.



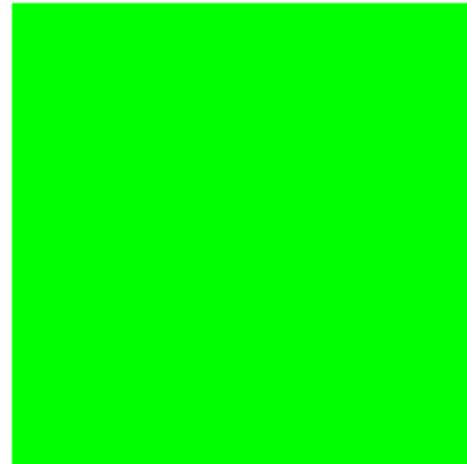
# PR Applied

The third photolithography process is done to remove the oxide, defining contact holes. The same procedure (PR Drop -> Spinning -> Pre-Baking -> Mask Alignment -> UV Exposure -> PR Developing -> Rinsing and Drying -> Post-Baking -> Oxide etching) as in lithography #1 is used.

PR applied.



Side View



Top View

■ P-type Silicon

■ N-type Silicon

■ Silicon Dioxide

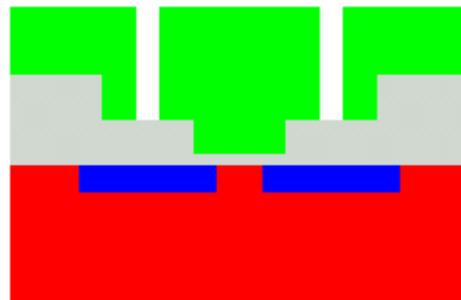
■ Photoresist

■ Aluminum

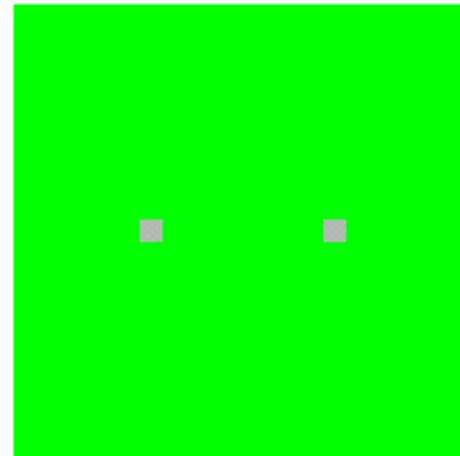
# PR Developed

The third photolithography process is done to remove the oxide, defining contact holes. The same procedure (PR Drop -> Spinning -> Pre-Baking -> Mask Alignment -> UV Exposure -> PR Developing -> Rinsing and Drying -> Post-Baking -> Oxide etching) as in lithography #1 is used.

PR developed.



Side View



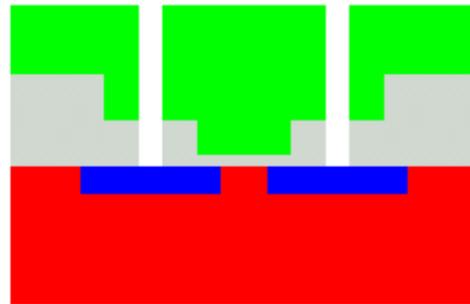
Top View

■ P-type Silicon    ■ N-type Silicon    ■ Silicon Dioxide    ■ Photoresist    ■ Aluminum

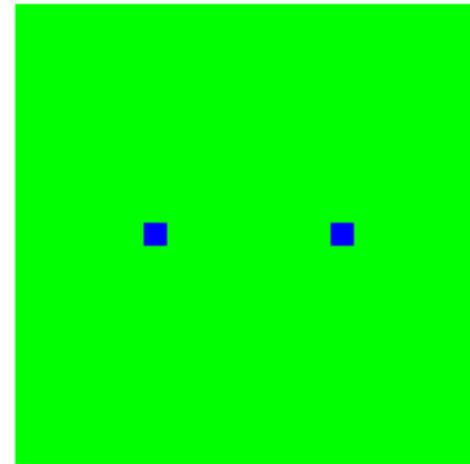
## Oxide Etched

The third photolithography process is done to remove the oxide, defining contact holes. The same procedure (PR Drop -> Spinning -> Pre-Baking -> Mask Alignment -> UV Exposure -> PR Developing -> Rinsing and Drying -> Post-Baking -> Oxide etching) as in lithography #1 is used.

Oxide etched.



Side View

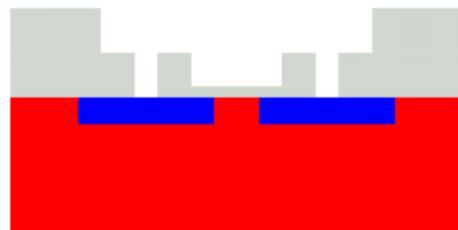


Top View

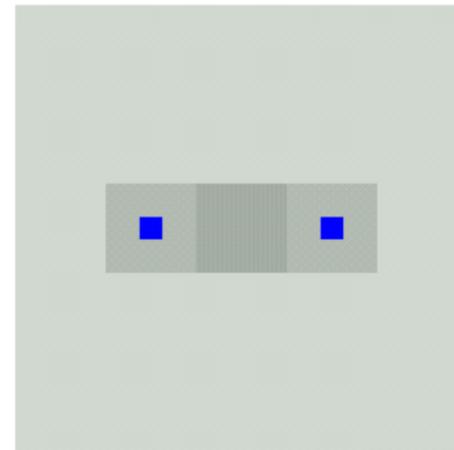
## PR Removed

The third photolithography process is done to remove the oxide, defining contact holes. The same procedure (PR Drop -> Spinning -> Pre-Baking -> Mask Alignment -> UV Exposure -> PR Developing -> Rinsing and Drying -> Post-Baking -> Oxide etching) as in lithography #1 is used.

PR removed.



Side View

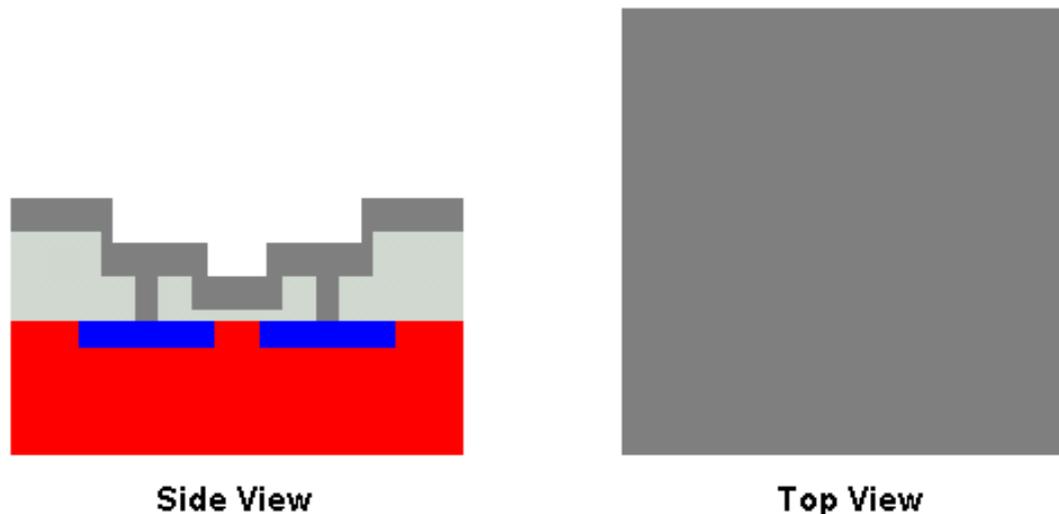


Top View

## Aluminium Film Deposited

A metal such as Aluminum is then evaporated on the whole substrate surface (a few thousand angstrom thick) under high-vacuum condition. This method is attractive because it is simple and inexpensive and produces no ionizing radiation. The Al layer will form electrical contacts later.

Aluminium film deposited.

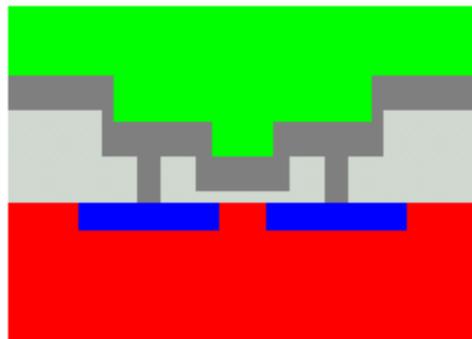


■ P-type Silicon    ■ N-type Silicon    ■ Silicon Dioxide    ■ Photoresist    ■ Aluminum

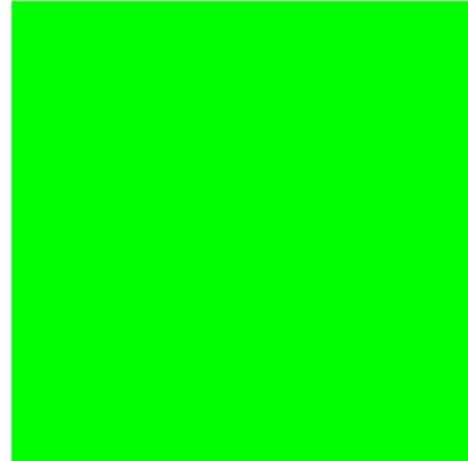
# PR Applied

The final lithography process is done to remove the Al-layer, defining a contact pattern. The same procedure( PR Drop -> Spinning -> Pre-Baking ->Mask Alignment ->UV Exposure ->PR Developing->Rinsing and Drying->Post-Baking ->Aluminum Etching) as in lithography #1 is used.

PR applied.



Side View

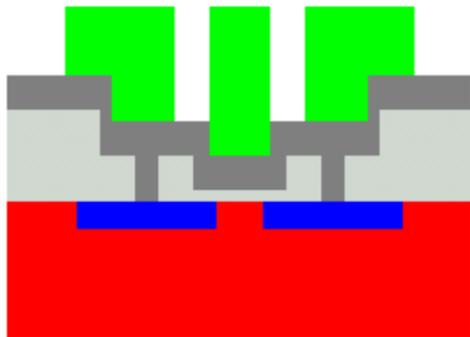


Top View

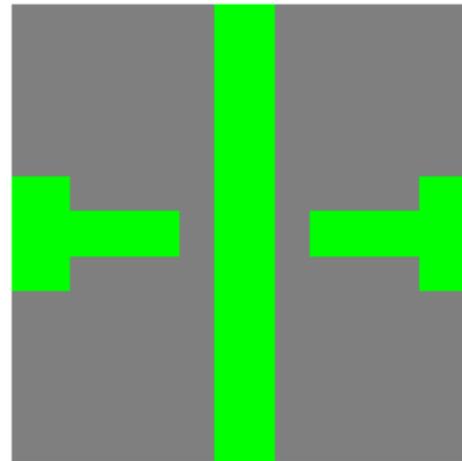
# PR Developed

The final lithography process is done to remove the Al-layer, defining a contact pattern. The same procedure( PR Drop -> Spinning -> Pre-Baking ->Mask Alignment ->UV Exposure ->PR Developing->Rinsing and Drying->Post-Baking ->Aluminum Etching) as in lithography #1 is used.

PR developed.



Side View

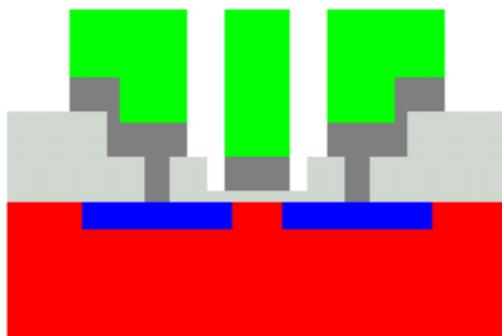


Top View

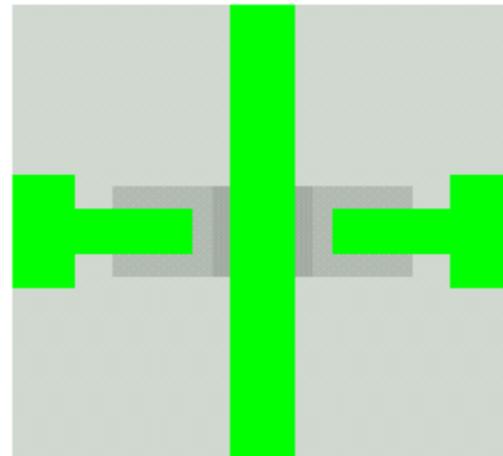
# Aluminum Interconnect Etched

The final lithography process is done to remove the Al-layer, defining a contact pattern. The same procedure( PR Drop -> Spinning -> Pre-Baking ->Mask Alignment ->UV Exposure ->PR Developing->Rinsing and Drying->Post-Baking ->Aluminum Etching) as in lithography #1 is used.

**Aluminium Interconnect etched.**



**Side View**



**Top View**

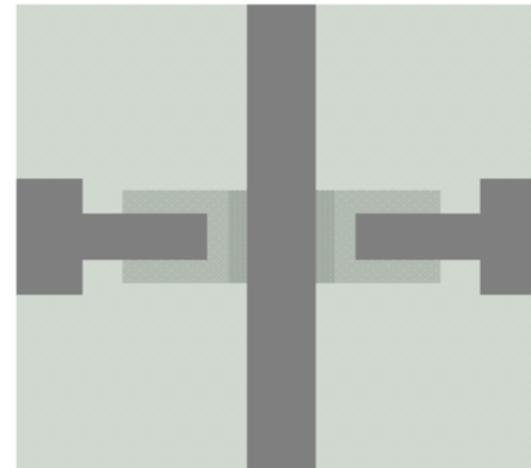
# Completion of NMOS Fabrication

After the final PR stripping, all the NMOS fabrication steps are completed.

## COMPLETION OF NMOS FABRICATION



Side View



Top View

■ P-type Silicon

■ N-type Silicon

■ Silicon Dioxide

■ Photoresist

■ Aluminum